

Notice of References Cited

Application/Control No.

10/786,158

Applicant(s)/Patent Under
Reexamination
BEAN ET AL.

Examiner

Alvin C. Chin-Shue

Art Unit

3634

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0200644 A1	10-2004	Paine et al.	177/136
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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